

IN THE CLAIMS

Please amend claim 1, and cancel claims 3 and 14-21 as follows:

1. (Currently Amended) A method for use in making a read head, comprising:

forming a read sensor which is abutted by longitudinal bias layers and has a trackwidth region;

depositing lead layers selectively over the longitudinal bias layers, without a resist or other mask structure formed over the trackwidth region, and without depositing lead layers over the trackwidth region, using a silicon reduction process and a hydrogen reduction process;

wherein the read sensor is formed in a top-type configuration with one or more free layers in a lower portion thereof; and

wherein the longitudinal bias layers have a midplane in alignment with the one or more free layers.

2. (Previously Presented) The method of claim 1, wherein the acts of depositing the lead layers selectively over the longitudinal bias layers comprises the further acts of performing the silicon reduction process and subsequently performing the hydrogen reduction process.

3. (Canceled)

4. (Previously Presented) The method of claim 1, further comprising:

wherein the longitudinal bias layers are deposited in side regions of the read sensor with use of a resist without undercuts over the read sensor in a central region; and

prior to selectively depositing the lead layers, removing the resist without undercuts.

5. (Original) The method of claim 1, wherein the act of selectively depositing the lead layers with use of the silicon reduction process comprises the further acts of:

depositing a silicon reactant layer over the longitudinal bias layers; and
passing a carrier gas which includes lead layer material so that the carrier gas is chemically reduced by the silicon.

6. (Original) The method of claim 1, wherein the act of selectively depositing the lead layers with use of the silicon reduction process comprises the further acts of:

depositing a silicon reactant layer over the longitudinal bias layers;
passing a carrier gas which includes lead layer material so that the carrier gas is chemically reduced by the silicon; and
wherein the lead layer material comprises tungsten (W).

7. (Original) The method of claim 1, wherein the act of selectively depositing the lead layers with use of the silicon reduction process comprises the further acts of:

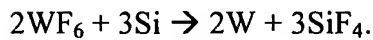
depositing a silicon reactant layer over the longitudinal bias layers;
passing a carrier gas which includes lead layer material so that the carrier gas is chemically reduced by the silicon; and
wherein the carrier gas comprises fluorine (F).

8. (Original) The method of claim 1, wherein the act of selectively depositing the lead layers with use of the silicon reduction process comprises the further acts of:

depositing a silicon (Si) layer over the longitudinal bias layers;

passing a carrier gas comprising fluorine (F) which includes lead layer material comprising tungsten (W) so that the carrier gas is chemically reduced by the silicon to selectively deposit the lead layers; and

wherein the following chemical reaction occurs in the silicon reduction process:



9. (Original) The method of claim 1, wherein the act of selectively depositing the lead layers with use of the hydrogen reduction process comprises the further acts of:

passing a hydrogen and a carrier gas which includes lead layer material, so that the carrier gas is chemically reduced by the hydrogen gas.

10. (Original) The method of claim 1, wherein the act of selectively depositing the lead layers with use of the hydrogen reduction process comprises the further acts of:

passing a hydrogen gas and a carrier gas which include fluorine (F) and tungsten (W), so that the carrier gas is chemically reduced by the hydrogen gas to selectively deposit a W film; and

wherein the following chemical reaction occurs in the hydrogen reduction process: $\text{WF}_6 + 3\text{H}_2 \rightarrow \text{W} + 6\text{HF}$.

11. (Original) The method of claim 1, further comprising:

wherein the read sensor abutted by longitudinal bias layers is formed by:

forming a plurality of read sensor layers over a wafer;

forming a photoresist over the read sensor layers in a central region;

ion milling, with the photoresist in place, so that read sensor layers in side regions are removed to thereby form the read sensor only in the central region;

with the photoresist in place, depositing the hard longitudinal layers in the side regions;

removing the photoresist;

after removing the photoresist, selectively depositing the lead layers over the longitudinal bias layers with use of the silicon reduction process and the hydrogen reduction process.

12. (Original) The method of claim 1, further comprising:

wherein the read sensor is formed in a top-type configuration with one or more free layers in a lower portion thereof; and

wherein the longitudinal bias layers comprise a Co-Pt-Cr film with a midplane in alignment with a midplane of the one or more free layers.

13. (Original) The method of claim 1, wherein the act of selectively depositing the lead layers is performed in an integrated high-vacuum physical-vapor-deposition (PVD)/chemical-vapor-deposition (CVD) system

14. (Canceled)

15. (Canceled)

16. (Canceled)

17. (Canceled)

18. (Canceled)

19. (Canceled)

20. (Canceled)

21. (Canceled)

22. (Original) A method for use in making a read head, comprising:
forming a read sensor which is abutted by longitudinal bias layers;
selectively depositing lead layers over the longitudinal bias layers with use of a silicon reduction process and a hydrogen reduction process, the silicon reduction process comprising the further acts of:
depositing a silicon reactant layer over the longitudinal bias layers; and
passing a carrier gas which includes lead layer material so that the carrier gas is chemically reduced by the silicon.

23. (Previously Presented) The method of claim 22, wherein the lead layers are selectively deposited over the longitudinal bias layers without a resist or other mask structure formed over the read sensor.

24. (Original) The method of claim 22, further comprising:
wherein the read sensor is formed in a top-type configuration with one or more free layers in a lower portion thereof; and
wherein the longitudinal bias layers have a midplane in alignment with the one or more free layers.

25. (Original) The method of claim 22, wherein the lead layer material comprises tungsten (W).

26. (Original) The method of claim 22, wherein the silicon reactant layer comprises a silicon (Si) layer, the carrier gas comprises fluorine (F), the lead layer material comprises tungsten (W), and the following chemical reaction occurs in the silicon reduction process: $2\text{WF}_6 + 3\text{Si} \rightarrow 2\text{W} + 3\text{SiF}_4$.

27. (Original) The method of claim 22, wherein the act of selectively depositing the lead layers with use of the hydrogen reduction process comprises the further acts of:

passing a hydrogen gas and a carrier gas which include fluorine (F) and tungsten (W), so that the carrier gas is chemically reduced by the hydrogen gas to selectively deposit a W film; and

wherein the following chemical reaction occurs in the hydrogen reduction process: $\text{WF}_6 + 3\text{H}_2 \rightarrow \text{W} + 6\text{HF}$.

28. (Original) A method for use in making a read head, comprising:

forming a read sensor which is abutted by longitudinal bias layers; and

selectively depositing lead layers over the longitudinal bias layers with use of a silicon reduction process and a hydrogen reduction process, the hydrogen reduction process comprising the further act of:

passing a hydrogen and a carrier gas which includes lead layer material, so that the carrier gas is chemically reduced by the hydrogen gas.

29. (Previously Presented) The method of claim 28, wherein the lead layers are selectively deposited over the longitudinal bias layers without a resist or other mask structure formed over the read sensor.

30. (Original) The method of claim 28, further comprising:

wherein the read sensor is formed in a top-type configuration with one or more free layers in a lower portion thereof; and

wherein the longitudinal bias layers have a midplane in alignment with the one or more free layers.

31. (Original) The method of claim 28, wherein the lead layer material comprises tungsten (W).

32. (Original) The method of claim 28, wherein the carrier gas comprises fluorine (F), the lead layer material comprises tungsten (W), and the following chemical reaction occurs in the hydrogen reduction process: $\text{WF}_6 + 3\text{H}_2 \rightarrow \text{W} + 6\text{HF}$.

33. (Original) The method of claim 28, further comprising:
wherein the read sensor abutted by longitudinal bias layers is formed by:
forming a plurality of read sensor layers over a wafer;
forming a photoresist over the read sensor layers in a central region;
ion milling, with the photoresist in place, so that read sensor layers in side regions are removed to thereby form the read sensor only in the central region;
with the photoresist in place, depositing the hard longitudinal layers in the side regions;
removing the photoresist; and
after removing the photoresist, selectively depositing the lead layers over the longitudinal bias layers with use of the silicon reduction process and the hydrogen reduction process.